

Issue Classification				Application/Control No.		Applicant(s)/Patent under Reexamination	
				10/500,608		KURITA, HIDEMI	
				Examiner		Art Unit	
				Devin Hanan		3745	

ORIGINAL				CROSS REFERENCE(S)			
CLASS	SUBCLASS	CLASS	SUBCLASS (ONE SUBCLASS PER BLOCK)				
415	4.2	415	4.4	907			
INTERNATIONAL CLASSIFICATION		416	44				
F	0	3	B	15/06			
F	0	3	D	7/06			
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			/				
			/				
<i>Devin Hanan 3/5/06</i> Devin Hanan 3/5/2006 (Assistant Examiner) (Date)				<i>Edward K. Look 3/6/06</i> EDWARD K. LOOK SUPERVISORY PATENT EXAMINER TECHNOLOGY CENTER 3700 (Primary Examiner) (Date)			
<i>K Cooper 3/6/06</i> K COOPER 3/6/2006 (Legal Instruments Examiner) (Date)				Total Claims Allowed: 11		O.G. Print Claim(s) 4	O.G. Print Fig. 1

<input type="checkbox"/> Claims renumbered in the same order as presented by applicant		<input type="checkbox"/> CPA		<input type="checkbox"/> T.D.		<input type="checkbox"/> R.1.47	
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8	8	38	68	98	128	158	188
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10	10	40	70	100	130	160	190
11	11	41	71	101	131	161	191
12	12	42	72	102	132	162	192
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